

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L9	553	(nesa adj glass) same electrode	US-PGPUB; USPAT	OR	ON	2005/03/15 14:14
L10	28	9 and electroluminescen\$2	US-PGPUB; USPAT	OR	ON	2005/03/15 14:14
L11	1	((electron adj microscop\$3) or SEM! or TEM!) and (protect\$3 same (platinum or Pt! or tungsten) same thickness)	JPO	OR	ON	2005/03/15 14:56
L12	352	((electron adj microscop\$3) or SEM! or TEM!) and (protect\$3 same (platinum or Pt! or tungsten) same thickness)	US-PGPUB; USPAT	OR	ON	2005/03/15 14:57
L13	0	".mu.m"	US-PGPUB; USPAT	OR	ON	2005/03/15 14:56
L14	0	".mu" adj m	US-PGPUB; USPAT	OR	ON	2005/03/15 14:57
L15	0	".mu"	US-PGPUB; USPAT	OR	ON	2005/03/15 14:57
L16	0	".mu."	US-PGPUB; USPAT	OR	ON	2005/03/15 14:57
L17	0	".mu. m"	US-PGPUB; USPAT	OR	ON	2005/03/15 14:57
L18	28359	"mu."	US-PGPUB; USPAT	OR	ON	2005/03/15 14:57
L19	440209	"mu.m"	US-PGPUB; USPAT	OR	ON	2005/03/15 14:57
L20	90	((electron adj microscop\$3) or SEM! or TEM!) and (protect\$3 same (platinum or Pt! or tungsten) same thickness same (19 or micron))	US-PGPUB; USPAT	OR	ON	2005/03/15 14:58
L21	23	((electron adj microscop\$3) or SEM! or TEM!) same sample) and (protect\$3 same (platinum or Pt! or tungsten) same thickness same (19 or micron))	US-PGPUB; USPAT	OR	ON	2005/03/15 15:03
L22	85	((electron adj microscop\$3) or SEM! or TEM!) same sample) and (protect\$3 same (platinum or Pt! or tungsten) same thickness)	US-PGPUB; USPAT	OR	ON	2005/03/15 15:03
S1	269	electroluminescen\$2 and (electron adj microscop\$3) and (mill\$3 or (focus\$6 adj ion adj beam\$3) or FIB!)	US-PGPUB; USPAT	OR	ON	2005/03/10 15:43
S2	365	electroluminescen\$2 and ((electron adj microscop\$3) or SEM or TEM) and (mill\$3 or (focus\$6 adj ion adj beam\$3) or FIB!)	US-PGPUB; USPAT	OR	ON	2005/03/10 13:09

S3	39	(organic adj electroluminescen\$2) and ((electron adj microscop\$3) or SEM or TEM) and (mill\$3 or (focus\$6 adj ion adj beam\$3) or FIB!)	US-PGPUB; USPAT	OR	ON	2005/03/10 13:25
S4	38261	((electron adj microscop\$3) or SEM or TEM) and (mill\$3 or (focus\$6 adj ion adj beam\$3) or FIB!)	USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/10 13:20
S5	11923	((electron adj microscop\$3) or SEM or TEM) and ((milling or milled) or (focus\$6 adj ion adj beam\$3) or FIB!)	USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/10 13:20
S6	11570	((electron adj microscop\$3) or SEM! or TEM!) and ((milling or milled) or (focus\$6 adj ion adj beam\$3) or FIB!)	USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/10 13:20
S7	156	((electron adj microscop\$3) or SEM! or TEM!) and ((milling or milled) or (focus\$6 adj ion adj beam\$3) or FIB!)	JPO	OR	ON	2005/03/10 13:24
S8	6	((electron adj microscop\$3) or SEM! or TEM!) and (((milling or milled) or (focus\$6 adj ion adj beam\$3) or FIB!) same protect\$3)	JPO	OR	ON	2005/03/15 14:55
S9	1634	((electron adj microscop\$3) or SEM! or TEM!) and (((milling or milled) or (focus\$6 adj ion adj beam\$3) or FIB!) same protect\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/14 14:01
S10	1	(organic adj electroluminescen\$2) and S9	US-PGPUB; USPAT	OR	ON	2005/03/10 13:25
S11	389	((electron adj microscop\$3) or SEM! or TEM!) same sample) and (((milling or milled) or (focus\$6 adj ion adj beam\$3) or FIB!) same protect\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/14 18:44
S12	4649	((electron adj microscop\$3) or SEM! or TEM!) same sample) and ((milling or milled) or (focus\$6 adj ion adj beam\$3) or FIB!)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/14 14:01
S13	157	((electron adj microscop\$3) or SEM! or TEM!) same sample) and (((milling or milled) or (focus\$6 adj ion adj beam\$3) or FIB!) same protect\$3) and (protect\$3 same (tungsten or W! or platinum or PT!))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/14 19:05

S14	390	((electron adj microscop\$3) or SEM! or TEM!) same sample) and (((milling or milled or mills) or (etching or etched or etches) or (thin\$1ing or thin\$1ed or thins) or (slicing or slices or sliced) or (focus\$6 adj ion adj beam\$3) or FIB!) same coarse same fine)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/14 19:38
S15	216	((electron adj microscop\$3) or SEM! or TEM!) same sample) and (((milling or milled or mills) or (etching or etched or etches) or (thin\$1ing or thin\$1ed or thins) or (slicing or slices or sliced) or (focus\$6 adj ion adj beam\$3) or FIB!) same coarse same fine)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/14 19:42
S16	11	((electron adj microscop\$3) or SEM! or TEM!) same sample) and (((milling or milled or mills) or (etching or etched or etches) or (thin\$1ing or thin\$1ed or thins) or (slicing or slices or sliced) or (focus\$6 adj ion adj beam\$3) or FIB!) same coarse same fine same (intermediate or medium!))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/14 19:42
S17	9	((electron adj microscop\$3) or SEM! or TEM!) same sample) and (((milling or milled or mills) or (etching or etched or etches) or (thin\$1ing or thin\$1ed or thins!) or (slicing or slices or sliced) or (focus\$6 adj ion adj beam\$3) or FIB!) same coarse same fine same (intermediate or medium!))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/14 19:42
S18	176	((electron adj microscop\$3) or SEM! or TEM!) same sample) and (((milling or milled or mills) or (etching or etched or etches) or (thin\$1ing or thin\$1ed or thins!) or (slicing or slices or sliced) or (focus\$6 adj ion adj beam\$3) or FIB!) same coarse same fine)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/14 19:44
S19	92	((electron adj microscop\$3) or SEM! or TEM!) same sample) and (((milling or milled or mills!) or (etching or etched or etches) or (thin\$1ing or thin\$1ed or thins!) or (slicing or slices! or sliced) or (focus\$6 adj ion adj beam\$3) or FIB!) same coarse same fine)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/14 19:44
S20	1203	(427/66,68).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/03/14 19:52
S21	75	S20 and ((electron adj microscop\$) or TEM! or SEM!)	US-PGPUB; USPAT	OR	ON	2005/03/14 20:01

S22	2169	(313/504).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/03/14 20:01
S23	70	S22 and ((electron adj microscop\$) or TEM! or SEM!)	US-PGPUB; USPAT	OR	ON	2005/03/14 20:02
S24	57	S23 not S21	US-PGPUB; USPAT	OR	ON	2005/03/14 20:01
S25	17	S22 and (((electron adj microscop\$) or TEM! or SEM!) with section)	US-PGPUB; USPAT	OR	ON	2005/03/14 20:02